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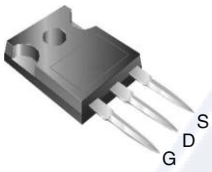
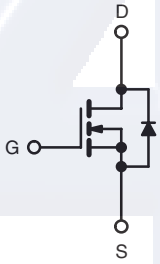
Power MOSFET

PRODUCT SUMMARY		
V_{DS} (V)	500	
$R_{DS(on)}$ (Ω)	V_{GS} = 10 V	0.27
Q_g (Max.) (nC)	105	
Q_{gs} (nC)	26	
Q_{gd} (nC)	42	
Configuration	Single	

TO-247





N-Channel MOSFET

FEATURES

- Low Gate Charge Q_g Results in Simple Drive Requirement
- Improved Gate, Avalanche and Dynamic dV/dt Ruggedness
- Fully Characterized Capacitance and Avalanche Voltage and Current
- Effective C_{oss} Specified
- Lead (Pb)-free Available

Available
RoHS* COMPLIANT

APPLICATIONS

- Switch Mode Power Supply (SMPS)
- Uninterruptable Power Supply
- High Speed Power Switching

TYPICAL SMPS TOPOLOGIES

- Full Bridge
- PFC Boost

ORDERING INFORMATION	
Package	TO-247
Lead (Pb)-free	IRP460APbF
	SiHFP460A-E3
SnPb	IRP460A
	SiHFP460A

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER			SYMBOL	LIMIT	UNIT
Drain-Source Voltage			V_{DS}	500	V
Gate-Source Voltage			V_{GS}	± 30	
Continuous Drain Current	V_{GS} at 10 V	T_C = 25 °C	I_D	20	A
		T_C = 100 °C		13	
Pulsed Drain Current[a]			I_{DM}	80	
Linear Derating Factor				2.2	W/°C
Single Pulse Avalanche Energy[b]			E_{AS}	960	mJ
Repetitive Avalanche Current[a]			I_{AR}	20	A
Repetitive Avalanche Energy[a]			E_{AR}	28	mJ
Maximum Power Dissipation	T_C = 25 °C		P_D	280	W
Peak Diode Recovery dV/dt[c]			dV/dt	3.8	V/ns
Operating Junction and Storage Temperature Range			T_J, T_{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s			300[d]	
Mounting Torque	6-32 or M3 screw			10	lbf · in
				1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
b. Starting T_J = 25 °C, L = 4.3 mH, R_G = 25 Ω, I_{AS} = 20 A (see fig. 12).
c. $I_{SD} \leq$ 20 A, dI/dt ≤ 125 A/µs, $V_{DD} \leq V_{DS}$, $T_J \leq$ 150 °C.
d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RATINGS				
PARAMETER	**SYMBOL**	**TYP.**	**MAX.**	**UNIT**
Maximum Junction-to-Ambient	R_{thJA}	-	40	°C/W
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.45	

SPECIFICATIONS T_J = 25 °C, unless otherwise noted							
PARAMETER	**SYMBOL**	**TEST CONDITIONS**		**MIN.**	**TYP.**	**MAX.**	**UNIT**
Static							
Drain-Source Breakdown Voltage	V_{DS}	V_{GS} = 0 V, I_D = 250 µA		500	-	-	V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I_D = 1 mA		-	0.61	-	V/°C
Gate-Source Threshold Voltage	$V_{GS(th)}$	V_{DS} = V_{GS}, I_D = 250 µA		2.0	-	4.0	V
Gate-Source Leakage	I_{GSS}	V_{GS} = ± 30 V		-	-	± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	V_{DS} = 500 V, V_{GS} = 0 V		-	-	25	µA
		V_{DS} = 400 V, V_{GS} = 0 V, T_J = 125 °C		-	-	250	
Drain-Source On-State Resistance	$R_{DS(on)}$	V_{GS} = 10 V	I_D = 12 A[b]	-	-	0.27	Ω
Forward Transconductance	g_{fs}	V_{DS} = 50 V, I_D = 12 A[b]		11	-	-	S
Dynamic							
Input Capacitance	C_{iss}	V_{GS} = 0 V, V_{DS} = 25 V, f = 1.0 MHz, see fig. 5		-	3100	-	pF
Output Capacitance	C_{oss}			-	480	-	
Reverse Transfer Capacitance	C_{rss}			-	18	-	
Output Capacitance	C_{oss}	V_{GS} = 0 V	V_{DS} = 1.0 V, f = 1.0 MHz		4430		
			V_{DS} = 400 V, f = 1.0 MHz		130		
Effective Output Capacitance	C_{oss} eff.		V_{DS} = 0 V to 400 V[c]		140		
Total Gate Charge	Q_g	V_{GS} = 10 V	I_D = 20 A, V_{DS} = 400 V, see fig. 6 and 13[b]	-	-	105	nC
Gate-Source Charge	Q_{gs}			-	-	26	
Gate-Drain Charge	Q_{gd}			-	-	42	
Turn-On Delay Time	$t_{d(on)}$	V_{DD} = 250 V, I_D = 20 A, R_G = 4.3 Ω, R_D = 13 Ω, see fig. 10[b]		-	18	-	ns
Rise Time	t_r			-	55	-	
Turn-Off Delay Time	$t_{d(off)}$			-	45	-	
Fall Time	t_f			-	39	-	
Drain-Source Body Diode Characteristics							
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode 		-	-	20	A
Pulsed Diode Forward Current[a]	I_{SM}			-	-	80	
Body Diode Voltage	V_{SD}	T_J = 25 °C, I_S = 20A, V_{GS} = 0 V[b]		-	-	1.8	V
Body Diode Reverse Recovery Time	t_{rr}	T_J = 25 °C, I_F = 20 A, dI/dt = 100 A/µs[b]		-	480	710	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	5.0	7.5	µC
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)					

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width ≤ 300 µs; duty cycle ≤ 2 %.

c. C_{oss} eff. is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 80 % V_{DS}.

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TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

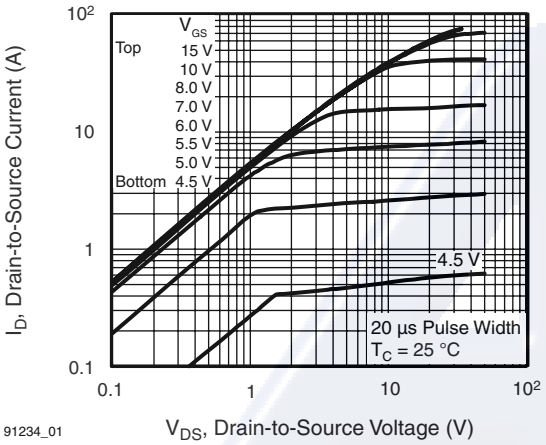

Fig. 1 - Typical Output Characteristics

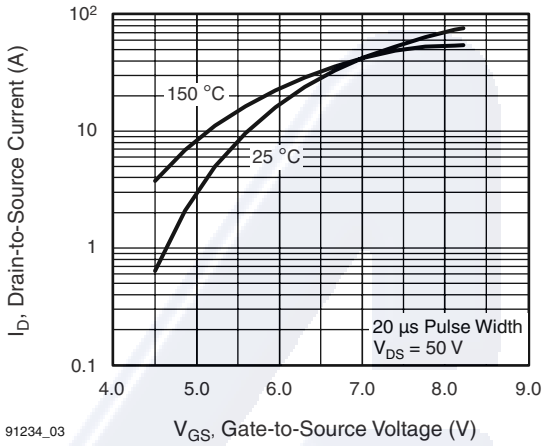

Fig. 3 - Typical Transfer Characteristics

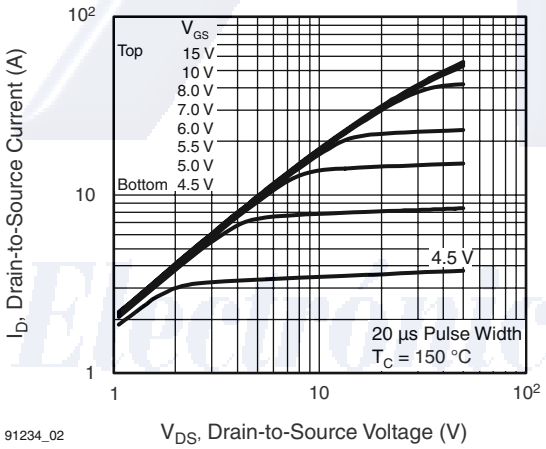

Fig. 2 - Typical Output Characteristics

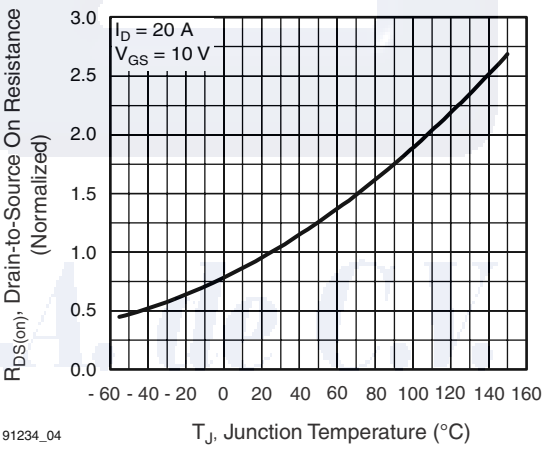

Fig. 4 - Normalized On-Resistance vs. Temperature

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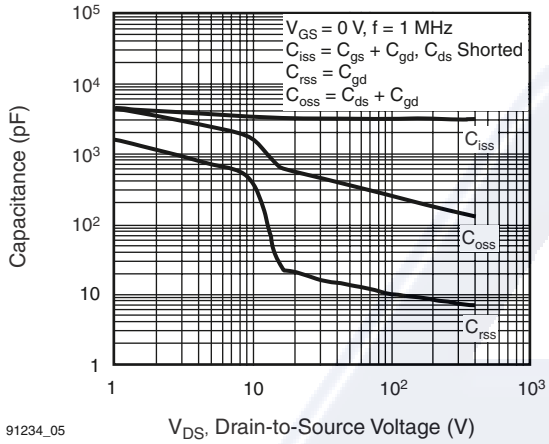

Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

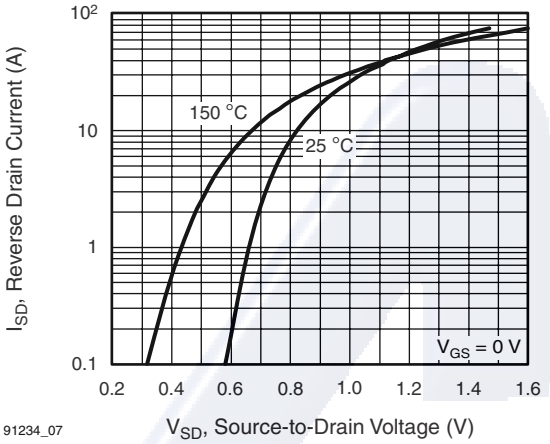

Fig. 7 - Typical Source-Drain Diode Forward Voltage

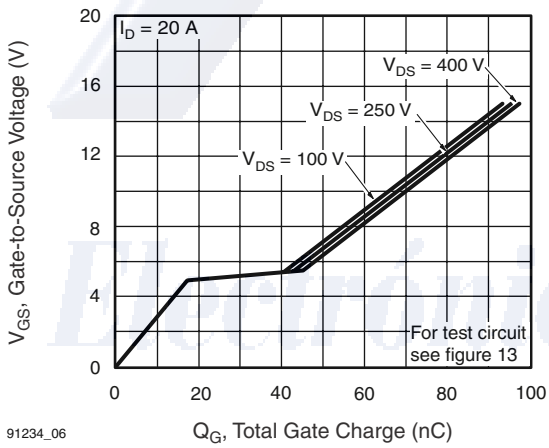

Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

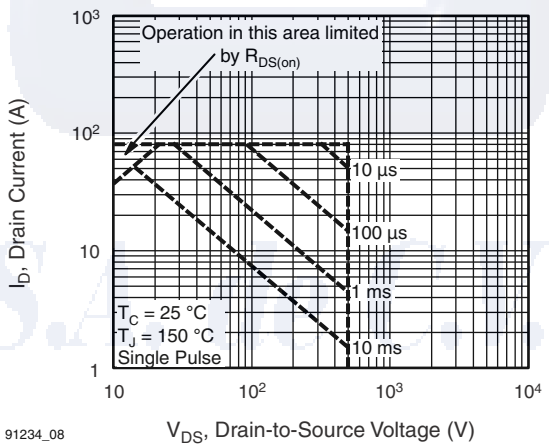

Fig. 8 - Maximum Safe Operating Area

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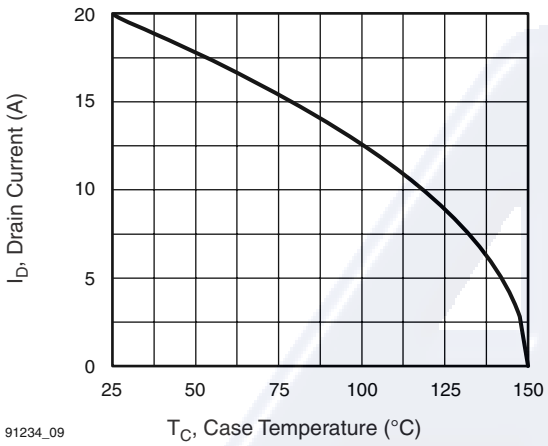

Fig. 9 - Maximum Drain Current vs. Case Temperature

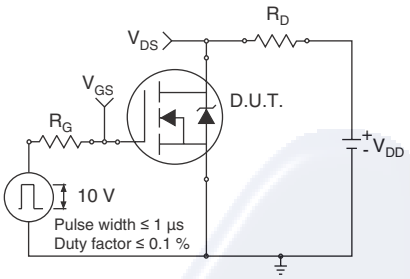

Fig. 10a - Switching Time Test Circuit

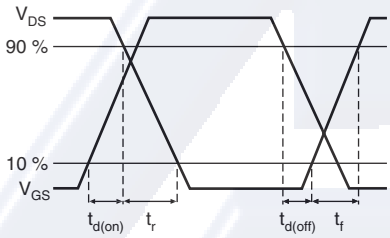

Fig. 10b - Switching Time Waveforms

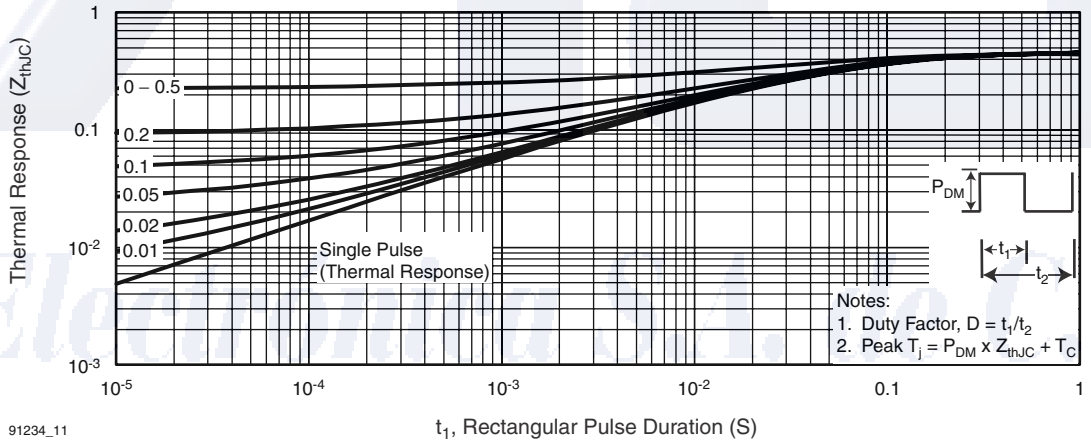

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

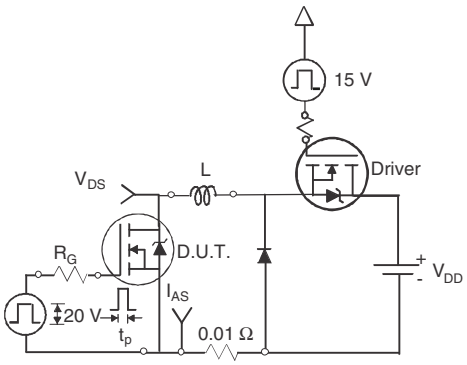

Fig. 12a - Unclamped Inductive Test Circuit

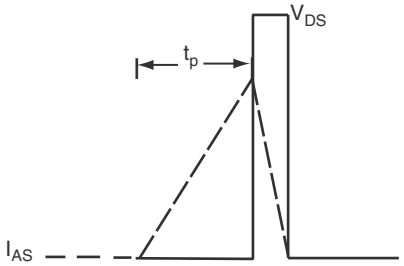

Fig. 12b - Unclamped Inductive Waveforms

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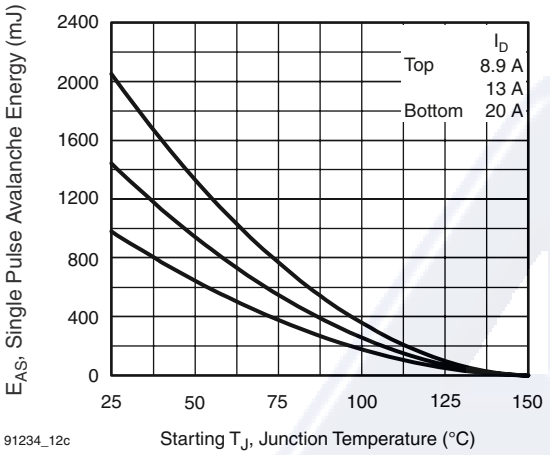

Fig. 12c - Maximum Avalanche Energy vs. Drain Current

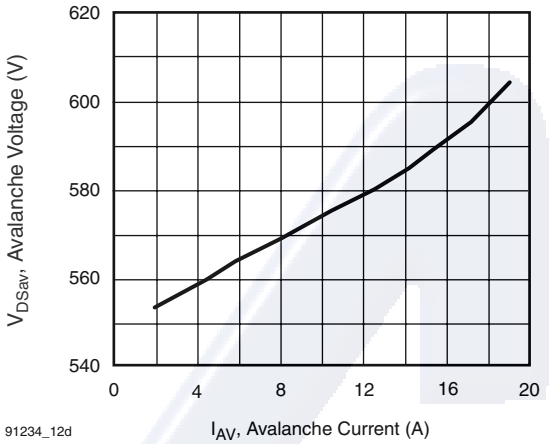

Fig. 12d - Typical Drain-to-Source Voltage vs. Avalanche Current

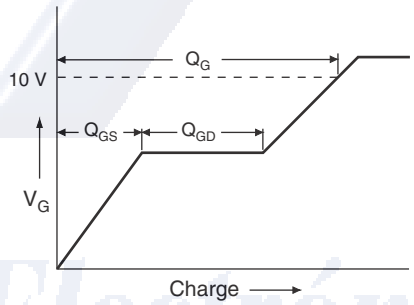

Fig. 13a - Basic Gate Charge Waveform

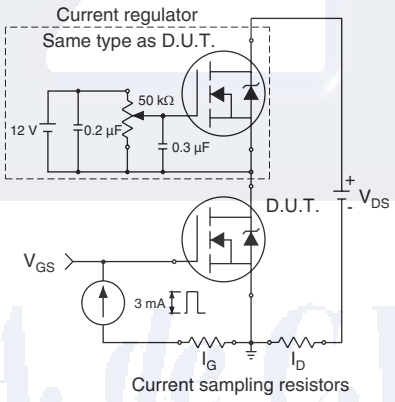

Fig. 13b - Gate Charge Test Circuit

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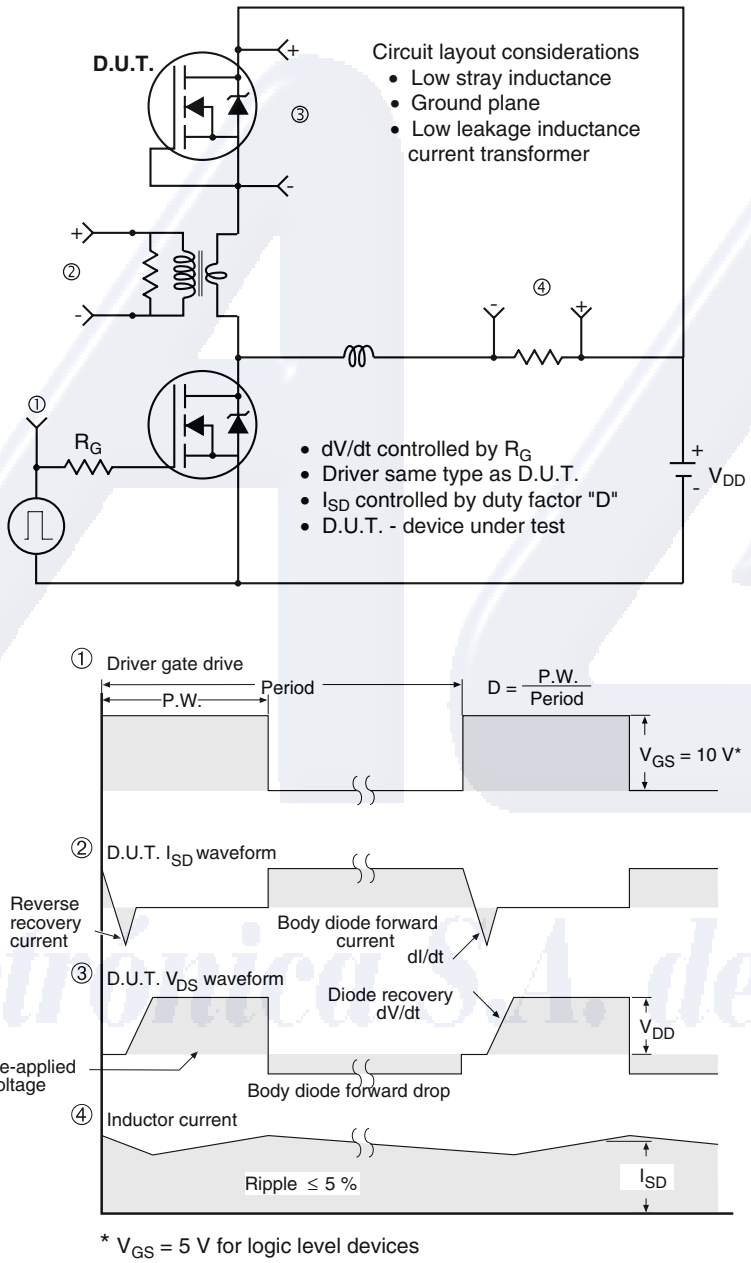
Peak Diode Recovery dV/dt Test Circuit



* V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

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